

## Semi-sesquicentennial of mecheng@IISc Distinguished Seminar Series



## Atomic Force Microscopy Related Techniques -application to Tribology, Colour Imaging and Artificial Reproduction Technology

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October 1, 2021 at 4:00 PM (IST)

Meeting link: <a href="https://bit.ly/3IV4kAE">https://bit.ly/3IV4kAE</a> (MS Teams)

## **ABSTRACT**

Abstract Atomic Force Microscopy (AFM) relies on detection of force at the atomic level for imaging with extremely high resolution. Due to this operating principle, the microscope offers a wide range of application in field of mechanical sensing in the sub-micron regime. I would like to introduce the application of the detection scheme to positioning, Tribology, multi-degrees of freedom force control, and colour imaging. I would also like to share preliminary results on « listening » to gametes or reproduction cells for future applications in artificial reproduction technology.



Session chair: Prof. M. S. Bobji, mecheng @ IISc